

DEFECTOMETER M PROBES

Flexible Probe Solutions for Mobile Eddy Current Testing



Eddy current probes for a wide range of inspection geometries

DEFECTOMETER M probes are designed for mobile eddy current inspections on a wide range of components and inspection areas. Probe elements are available in shielded and unshielded versions and can be integrated into various probe designs.

Shielded probes reduce magnetic field spread and enable inspections close to edges, corners and rivet heads.

Unshielded probes provide wider inspection coverage and are less sensitive to tilting or wobbling movements.

The probes are optimized for non-ferromagnetic, austenitic and ferromagnetic materials.

Straight, angled and flexible pencil probes are available for different inspection tasks. Angled versions improve accessibility in hard-to-reach areas, while flexible probes allow adaptation to complex geometries. Probe geometries can be customized in terms of angle, length and diameter.

Additional special probe types such as bolt-hole probes, micro probes, spring-loaded probes and probes for large crack depths are available for demanding inspection tasks.

All DEFECTOMETER M probes feature high sensitivity, robust construction and ergonomic handling. Preconfigured inspection kits are available for recurring applications.

YOUR ADVANTAGES AT A GLANCE

Flexible probe concepts: Different probe designs for a wide range of inspection tasks

Precise edge inspection: Shielded probes for inspections close to edges and geometry transitions

Stable inspection results: Unshielded probes reduce the influence of tilting and movement

Optimized for different materials: Suitable for non-ferromagnetic, austenitic and ferromagnetic materials

High accessibility: Straight, angled and flexible pencil probes for hard-to-reach inspection areas

Robust design: Developed for mobile industrial inspection applications

High inspection sensitivity: Reliable detection of near-surface defects and cracks

TECHNICAL INFORMATION

COMPATIBILITY:	DEFECTOMETER M 1.837 (and older versions); TCM
PROBE VERSIONS:	Shielded and unshielded probe elements
PROBE DESIGNS:	Straight, angled and flexible pencil probes
SPECIAL PROBE TYPES:	Bolt-hole, micro, spring-loaded and large crack depth probes
PROBE PROTECTION:	Optional ceramic wear protection
CONNECTIVITY:	Probe sockets, cables and adapter solutions available
MATERIALS:	Non-ferromagnetic, austenitic and ferromagnetic materials
CONDUCTIVITY RANGE – NFE PROBES:	4 to 60 MS/m (7 to 103 % IACS)
CONDUCTIVITY RANGE – AUSTENITIC PROBES:	0.5 to 4.5 MS/m (1 to 8 % IACS)
CONDUCTIVITY RANGE – FE PROBES:	6 to 10 MS/m (10 to 17 % IACS)
TEST FREQUENCIES:	2 MHz (NFe), 4 MHz (Austenitic / Fe)
ANGLED PROBES:	Available with 90°, 100° and 135° probe tip angles
FLEXIBLE PROBES:	Flexible gooseneck design with swiveling probe tip
CUSTOMIZATION:	Configurable probe geometries, angles, lengths and diameters
STANDARD CABLE LENGTH:	1.5 m
PROBE PROPERTIES:	High sensitivity, robust design and plug-in cable connection
ACCESSORIES:	Preconfigured inspection kits available

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